

## GRADUATE STUDENT AWARD FINALISTS—1995 MRS FALL MEETING

**Jamie J. Arnold**, Penn State University, "Are Single Molecular Wires Conducting?" (Symposium J)  
**Hamid Assadi**, University of Cambridge, "Competitive Phase Selection in Fe-Ni Alloy Droplets" and "Development of Microstructure in Rapidly Solidified Intermetallics," (Symposium C)  
**Greg Carlson**, University of Connecticut, "Polymer Nanocomposites of Surface-Functionalized Gold," (Symposium W)  
**Yong Chen**, University of California, "Artificially Ordered  $\text{AlAs}_{0.16}\text{Sb}_{0.84}$  and  $\text{InAs}_{0.93}\text{Sb}_{0.07}$  Alloys Grown by Modulated Molecular Beam Epitaxy," (Symposium EE)  
**Brian H. Cumpston**, Massachusetts Institute of Technology, "Stability of PPV Derivatives: The Effect of Side Group Functionalities" and "Photo-Oxidation of Polythiophenes on Metal Substrates," (Symposium W)  
**Partha Sarathi Dutta**, Indian Institute of Science, "Cathodoluminescence Spectroscopy for Evaluation of Defect Passivation in GaSb," (Symposium L)  
**Nora V. Edwards**, North Carolina State University, "Analysis of Strain in GaN on  $\text{Al}_2\text{O}_3$  and 6H-SiC," (Symposium AAA)  
**Michael V. Glazov**, University of Pennsylvania, "Temporal Instabilities (Dissipative Structures) in Cyclically Deformed Metallic Alloys," (Symposium Q)  
**Cécile Gourgon**, Université J. Fourier, "Strain Effects in CdTe/CdZnTe Nanostructures Fabricated by Nanolithography and Cleaved-Edge Overgrowth," (Symposium K)  
**Kalpna S. Katti**, University of Washington, "A Novel Technique for Determining Local Dielectric Function During Ferroelectric to Paraelectric Phase Transformation in  $\text{BaTiO}_3$  with a Transmission EELS," (Symposium T)  
**Matthew R. Linford**, Stanford University, "Light-Induced Formation of Alkyl Monolayers on Silicon," (Symposium O)

**Thomas S. McCauley**, University of Alabama, "High-Temperature Homoepitaxial Diamond Film Growth: Defects and Doping," (Symposium DD)  
**Sridhar Narayanaswamy**, University of Michigan, "Temporal Evolution of Particle Shape in a Stressed Solid," (Symposium C)  
**Ivan W. Ong**, The Johns Hopkins University, "Surface Enhanced Raman Spectroscopy of AgTCNQ Formed from Ag Micellar and Inverse Micellar Colloidal Systems," (Symposium W)  
**Daniel W. Pack**, California Institute of Technology, "Ligand-Induced Reorganization and Protein Assembly in Synthetic Metal-Chelating Lipid Membranes," (Symposium O)  
**Jeff Parrell**, University of Wisconsin, "Controlled Decomposition and Reformation of the 2223 Phase in Ag-Clad (Bi,Pb) $_2$ Sr $_2$ Ca $_2$ Cu $_3$ O $_x$  Tapes and Its Influence on the Microstructure and Critical Current Density," (Symposium F)  
**Fan Qian**, University of Florida, "Deposition of Diamond-Like Carbon Films with Femtosecond Laser Pulses," (Symposium B)  
**Sundar Ramamurthy**, University of Minnesota, "Interaction of Silicate Liquid with Sapphire Surfaces," (Symposium G)  
**Paul G. Sanders**, Northwestern University, "Structural Study of Nanocrystalline Cu, Pd, and Ni Compacts with Different Processing Histories," (Symposium E)  
**Steven R. Soss**, Rensselaer Polytechnic Institute, "Electron Transport in Highly Textured Metal Films Grown by Partially Ionized Beam Deposition," (Symposium I)  
**Bradford G. Storey**, Northwestern University, "Structural Features of Defect Cascades in  $\text{YBa}_2\text{Cu}_3\text{O}_x$  as a Function of Oxygen Stoichiometry" and "A TEM Study of the Modulated Phase in  $\text{Hg}_{1-x}\text{Cr}_x\text{Sr}_2\text{CuO}_{4+y}$  Superconductors," (Symposium F)

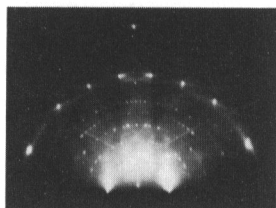
**Ellad B. Tadmor**, Brown University, "Multiple-Scale Quasi-Continuum Finite Element Analysis of Defects in Crystals," (Symposium P)  
**Hark Hoe Tan**, Australian National University, "Irradiation-Induced Damage and Intermixing of GaAs-AlGaAs Quantum Wells," (Symposium A)  
**Patrick Tepech**, Massachusetts Institute of Technology, "A General Model to Predict Defect Arrangements in Complex Oxides: Application to Defect Fluorites," (Symposium P)  
**Scott A. Walker**, University of California, "Ion-Driven Self-Assembly of Surfactant Mixtures into Ordered Phases," (Symposium N)  
**Ping-Chuan Wang**, Columbia University, "Grain Orientation Mapping for Polycrystalline Films with an X-Ray Microdiffraction System," (Symposium I)  
**K. Scott Weil**, Carnegie-Mellon University, "A Complexed Precursor Approach to the Synthesis of Ternary Transition Metal Nitrides," (Symposium S)  
**Yongwu Yang**, Massachusetts Institute of Technology, "Slow Relaxation Dynamics from Impulsive Stimulated Light Scattering Experiments," (Symposium M)  
**Zheng Jun Zhang**, Tsinghua University, "Role of Interface in Ion Mixing/Thermal Annealing Induced Amorphization in Multilayers in Some Immiscible Metal Systems" and "Study of Metastable Alloy Formation in an Immiscible Y-Zr System by Ion Mixing/Thermal Annealing," (Symposium A)  
**Qun Zhong**, University of Houston, "Defects in High-Temperature Superconductors: Characterization and Relations to Processing and Properties," (Symposium F)

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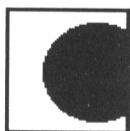


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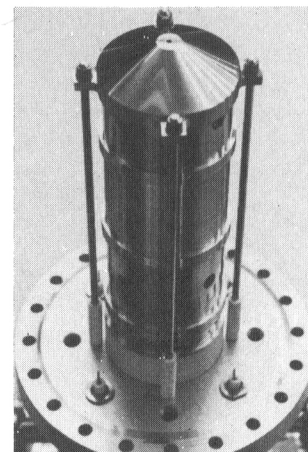
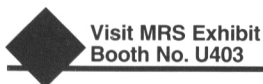
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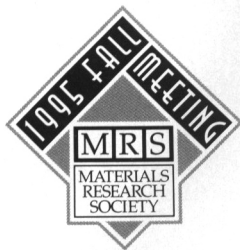


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# MRS Exhibit

**Boston Marriott Hotel and Westin Hotel/Copley Place • Sheraton Boston Hotel**

As part of the 1995 MRS Fall Meeting, a major exhibit will be held to display analytical and processing equipment and publications closely paralleling the nature of the technical symposia. The technical program has been arranged to allow meeting participants ample opportunity to visit the exhibit.

## Exhibit Hours:

### Marriott Hotel, University Hall & Atrium Lounge

Tuesday, noon - 7:00 p.m.  
**Complimentary Reception 5:00 - 7:00 p.m.**  
 Wednesday, 9:30 a.m. - 5:00 p.m.  
 Thursday, 9:30 a.m. - 2:00 p.m.

### Westin Hotel, 3 & 4 Fl./Sheraton Hotel, Republic Foyer

Tuesday, 9:30 a.m. - 5:00 p.m.  
 Wednesday, 9:30 a.m. - 12:30 p.m.  
 and 7:30 p.m. - 10:00 p.m.  
 Thursday, 9:30 a.m. - 12:30 p.m.

## Partial List of 1995 Fall Exhibitors (as of October 2, 1995):

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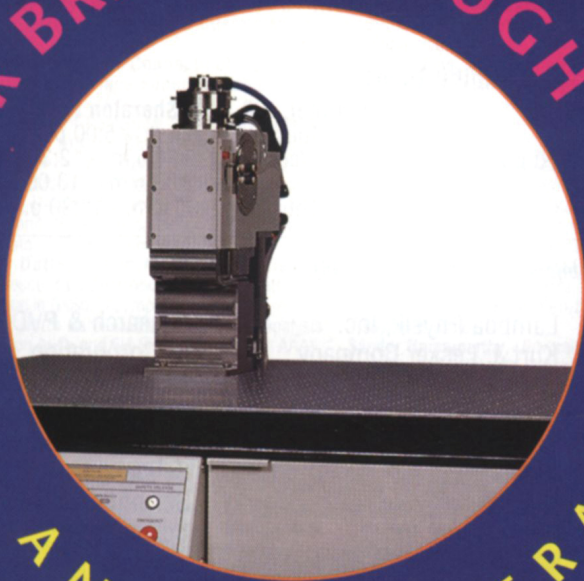
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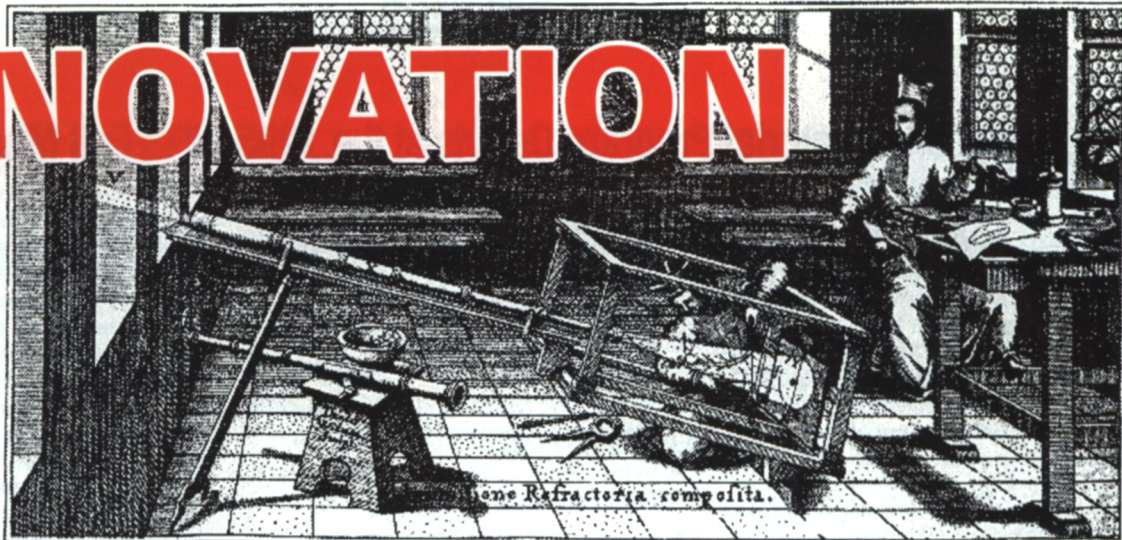
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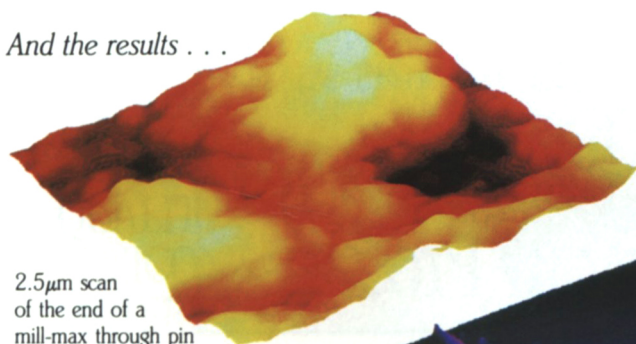


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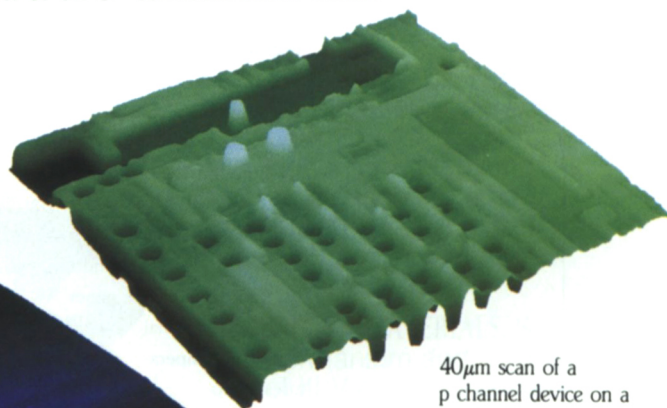
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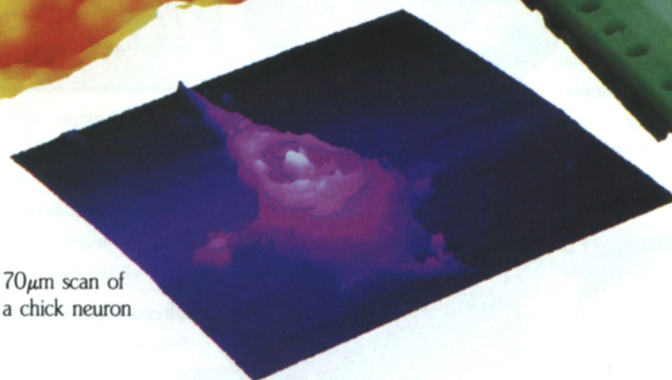
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